Q.2a. Discuss factors affecting the Resistivity of conducting materials.

2.2. Factors Affecting the Resistivity of Electrical Materials

(i) Temperature. The electrical resistance of most metals increases with increase of temperature whilst those of semiconductors and electrolytes decreases with increase of temperature. Many metals have vanishing resistivity at absolute zero of temperature. The phenomenon is known as superconductivity.

(ii) Alloying. A solid solution has a less regular structure than a pure metal. Consequently, the electrical conductivity of a solid solution alloy drops off rapidly with increased alloy content. In other words, the addition of small amounts of impurities leads to a considerable increase in resistivity. For example, brass (63% Cu and 40% Zn), which is widely used as a contact material in power plugs and sockets has a resistivity of 9 μ ohm-cm which however is not in direct proportion to the amounts of the different metals in the alloy.

The high conductivity in metals is associated with the presence of these "free" or conduction electrons. The only electrons having this high degree of freedom are those corresponding to the valence electrons in the atoms. Thus, one may think of a metal as consisting of a lattice of positive ion cores held together by means of a gas of electrons. These are constant collisions between the electrons and the atoms. Lattice spacing in copper is about 3.6A. Electrons may travel one or two atomic diameters, but mean free path is several hundred atomic spaces. In a copper nickel alloy the copper atoms do not impede the motion of the free electrons, but additional nickel atoms impede their motion.

The temperature coefficient of metals is very small. It is therefore not surprising that the increase in resistivity due to the addition of impurities is temperature independent. This suggests the existence of alloys whose resistance varies little with temperature. See Table $2\cdot 2$. 90

(iii) Cold Work. Mechanical distortion of the crystal structure

decreases the conductivity of a metal because the localized strains interfere with electron movement. Thus hard drawn copper wire has a lower conductivity than annealed copper. Subsequent annealing restores the electrical conductivity by establishing greater regularity in the crystal lattice.

Hard drawn copper has a resistivity of 1.9×10^{-6} ohm-cm at 20°C whereas annealed copper has a resistivity of 1.72×10^{-6} ohm cm at 20°C.

(iv) Age Hardening. Age hardening increases the resistivity of an alloy.

No. 1. 2.1 The existivity of pure conner is 1.56 micro-ohm-

b. What is contact potential? Draw & explain energy distribution of electrons in two metals before & after contact.



Q.3 a. Discuss the effect of dielectric on the behaviour of a capacitor.

Suppose that two large plane parallel plates separated by a distance d (metres) in vacuo are maintained at a potential difference V. The plates will become charged positively and negatively with charges $\neq Q_0$ and a uniform electric field with intensity E=V/d (volts/m) will be created between the plates. The magnitude of the charge accumulated on each plate is proportional to the applied p.d., *i.e.*, $Q_0 \propto V$ or $Q_0 = C_0 V$, where C_0 is defined as the capacitance.

'By applying Gauss's theorem it will be seen that the magnitude of the flux density D within the parallel plates is given by

$$D = \frac{Q_0}{A}$$

Since the electric field strength E is related to the flux density by the relation $D = \in_0 E$, the field strength in the region between the plates is given by $E = D/\in_0 = Q_0/A \in_0$. Since V = Ed, the capacitance of the system is given by $C_0 = \in_0 A/d$ where \in_0 is termed the absolute permittivity of free space and is expressed in farads/ metre. The value of \in_0 can be determined from experiment and is

found to be nearly equal to $\frac{10^{-9}}{36\pi}$

If the space between the plates is now filled with a dielectric and V is kept constant, it is found that the value of the pharge is increased to a value given by Q = CV.

It follows that the new capacitance is given by $C = \in A/d$ where \in is defined as the absolute permittivity of the dielectric and the ratio $\in_r = C/C_0 = \in /\in_0$ is called the relative permittivity, specific inductive capacity or the dielectric constant of the material. \in_r can be determined experimentally by measuring the capacities with and without the dielectric respectively. The dielectric constant varies between 1 and 10 for normal solid substances. It is greater than 10 for liquids such as ethyl alcohol, glycerine and water and his still higher values for gases at high frequencies. It is 1 for vacuum and about 1.0057 for air at N.T.P. It varies not only from substance to substance, but also with the physical state of any particular substance. The dielectric constant of a medium is constant if the state of the medium does not vary from point to point. At the boundary between two media the dielectric constant changes abruptly, and bodies that are non-homogeneous with respect to the dielectric constant as well.

b. Derive Clausius-Mossotti relation.

of a molecule.

4.6. The internal field in solids and liquids

Each dipole moment interacts with its neighbour through its local electric field and therefore the theory of dielectrics in the case of dense substances such as solids or liquids where the dipoles are close together is much more complicated than that for rarefied substances. The main problem which arises in the case of solids and liquids is the calculation of what is known as the internal, local or the Lorentz field, E_i , which is defined as the field acting at the location of a given atom. In gases, the density of the molecules is reasonably low and we are therefore justified in assuming that the internal field is equal to the applied field. However, in solids and liquids the molec⁻¹ s are so close together that the field

d

e.

nt

ELECTRICAL ENGINEERING MATERIALS 146 seen by a given particle is determined in part by the dipoles carried by the surrounding particles; in general therefore the internal field E_4 is not equal to the applied field E. The dipole moment, m, induced in each of the atoms of a string of atoms of polarisability α is thus given by $m = \alpha |E_i|$ If there are N dipoles per m³ P = Nm $=N\alpha E_i$ This enables us to derive a relationship between the measured dielectric constant \in , in terms of the polarisability, α . [where E is external $D = \in_0 E + P$ Thus applied field] $= \in_0 E + N \alpha E_i$ The observed dielectric constant is defined by $D = \in_0 \in rE$ $\in_r = 1 + \frac{N\alpha}{\in_0} \frac{|E_i|}{|E|}$...(8) Hence In order to determine \in , from the observed experimental data, it is first necessary to determine the internal field $|E_i|$. The internal field $|E_i|$ is equal to the applied field |E|plus the field produced at the location of the particular atom by the dipoles on all other atoms. As a first approximation, the field produced due to the dipoles can be expressed in terms of the polarisation, P. $E_i = E + \frac{v}{\epsilon_0}P$ or, where v is a proportionality constant which takes on different values depending upon the particular symmetry conditions which are met. For the special case of an isotropic substance or for one having cubic symmetry, $\nu = \frac{1}{3}$ $E_i = E + \frac{P}{3 \in 0}$...(9) and Equation (9) along with the equation $P = N\alpha L_{i}$ $E_{i} = \frac{E}{1 - \frac{N\alpha}{3 \in 0}}$ $P = N\alpha E_i$ gives which along with equation (8) gives $\begin{array}{c} \text{ion (8) given} \\ \in r = \frac{1 + \frac{2N\alpha}{3 \in \circ}}{1 - \frac{N\alpha}{1 \in \circ}} \end{array}$









MAGNETIC PRC RTIES OF MATERIALS

permeability is defined as the slope of the normal magnetisation curve, at H=O. The incremental permeability is defined as $\triangle B$ about a given point on the hysterisis loop. Sometimes the term differential permeability is used; it is defined as dB/dH, the slope of the magnetisation curve at the point of interest.

Another classification of magnetic materials consists in the presence or absence of permanent magnetic dipoles in them : the term permanent magnetic dipole being used in the same sense as in the corresponding dielectric case, *i.e.* a permanent dipole exists in the absence of a field. Materials which lack permanent magnetic dipoles are called diamagnetic. Magnetisation of such materials occurs when the applied field induces a magnetic moment in the individual atoms.

This possibility arises since an external magnetic field may cause changes in the electron orbits. In the absence of the external field the net magnetic moment of the orbits is zero but takes a nonzero value when the orbits are charged.

If permanent magnetic dipoles are present in the atoms of a material, it may be paramagnetic, ferromagnetic, antiferromagnetic or ferrimagnetic depending on the interaction between the individual dipoles, Thus if the interaction between the atomic permanent dipole moments is zero or negligible and the individual dipole moments are oriented at random as shown in Fig. 6.3 (a) the material will be paramagnetic. If the dipoles interact in such a manner that they tend to line up in parallel, as shown in Fig. 6.3. (b) the material will be ferromagnetic. Such materials exhibit what is known as ordered magnetism because of the stronger interatomic interaction. When neighbouring moments are aligned antiparallel as in Fig. 6.3 (c), the magnetic phenomenon is known as antiferromagnetism. In ferromagnetic materials there is a large resultant magnetisation whereas in antiferromagnetic materials, the magnetisation vanishes. When the order of the magnetic moments is as shown in Fig. 6.3(d) the phenomenon is known as ferrimagnetism. For ferromagnetic materials [Fig. 6.3 (b)] if the four atoms comprise one molecule, the molecular moment will be four times the atomic moment. For antiferromagnetic materials the molecular moment will be zero and there is no spontaneous magnetisation. The molecular moments in ferrimagnetic materials



Fig. 6.3. Paramagnetic, ferromagnetic, anti-ferromagnetic and ferrimagnetic arrangement of spins.

will have values in between the values for ferromagnetic and antiferromagnetic materials.

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...(1)

the valence and conduction bands overlap. An insulator is a material in which the energy gap is so large that practically no electron can be given enough energy to jump this gap. These materials might conduct little electricity if their temperatures are raised to very high values enabling a number of electrons to join the conduction band.

A semiconductor is a solid with an energy gap small enough for electrons to cross rather easily from the valence band to the conduction band. At room temperature, sufficient energy is available for a few valence electrons to bridge the energy gap to the conduction band, thus the material sustains some electric current.

It is clear that an allowed energy band in a solid contains a large number of individual energy levels. Therefore the energy of an electron in a solid may take one value of a number of closely spaced values within these permitted bands. Naturally it may not take values laying within the forbidden energy bands. Electrons fill up energy positions starting from the lowest possible levels. At 0° K these levels are completely occupied by electrons up to a certain level, and completely unoccupied above it. The highest level completely filled by electrons is the Fermi level.

The energy distribution of electrons in a solid are governed by the laws of Fermi-Dirac statistics. The principal result of these statistics is the Fermi-Dirac distribution function which determines the probability that a given energy state is occupied by an electron.

 $f(E) = 1/[1 + \exp((E - E_F)/kT)]$

where f(E) is the probability that an electronic state with energy E is occupied by an electron.

EF is the Fermi level, or the Fermi energy.

k Boltzmann's constant.

The Fermi level is such that, at any temperature, the number of electrons with greater energy than the Fermi energy is equal to the number of unoccupied energy levels lower than this. In conductors the Fermi level is situated in a permitted band (since the valence band and conduction band overlap with no energy gap). In insulators it lies in the centre of the large energy gap while in semiconductors it lies in the relatively small energy gap.

b.Explain the following:

(i) Thermal conductivity of semiconductors

(ii) Electrical conductivity of doped material

7.1. Thermal conductivity of semi-conductors

Heat conduction in semi-conductors takes place in two ways (i) by the electrons, and (ii) by the thermal vibrations of the atoms. The random thermal vibrations of all the atoms of a semi-conductor may be regarded as the sum total of vibrations of individual atoms, vibrations of pairs of atoms, of groups of three and ultimately the vibrations of the body as a whole. The higher the temperature the greater are these vibrations.

The coefficient of thermal conductivity of a semi-conductor consists of two parts (i) the thermal conductivity due to the electrons and (H) the thermal conductivity due to the thermal vibrations of the atoms. When the concentration of free electrons in semi.

conductor varies, the thermal conductivity due to the electrons varies in direct proportion to the electrical conductivity (cf Wiedemann-Franz law for metals) whereas the thermal conductivity due to vibrations of atoms remains practically constant. The Weidemann-Franz Law for metals is $K/\sigma = A_m$. T where A_m is a constant for all metals. This law as applied to semi-conductors is modified to $K = A_s T.\sigma + K_{lh}$ where A_s is a constant corresponding to the semi-conductors and K_{sh} is the contribution to thermal conductivity due to vibrations.

7.12. Electrical conductivity of doped materials

A semi-conductor may be doped with donors or acceptors in which case the density of one type of carrier predominates. Thus in the presence of donor levels, the electrons are the majority carriers and in the presence of acceptor levels, the holes are the majority carriers. The free carrier concentration given by impurity atoms whose valence electrons have an energy less by $\triangle E_1$ than their energy in the free state is

$$n_e = A_1 \exp\left(-\frac{\triangle E_1}{2KT}\right)$$

The valence band, also, always contains a certain number of holes. It may be shown that the electron and hole concentrations are related by

$$n_e n_h = n_i^2$$

where $n_i = A \exp(-\Delta E/2KT)$ is the concentration of either electrons or holes when no impurities are present and ΔE is the width of the forbidden energy gap.

The product of the two concentrations does not depend upon the number of impurity atoms nor on the electron energies of such atoms. It always equals the square of the free electron or hole concentration for the pure semi-conductor at that temperature.

If the impurity atoms are electronegative the hole concentration will be

$$n_h = A_2 \exp(-\triangle E/2KT)$$

and the electron concentration in such a case would be

 $n_e = n_i^2/n_h$

If a semi-conductor contains N_1 electropositive impurity levels per m^3 and N_2 electronegative levels per m^3 and if $N_1 > N_2$ then the electrons given by the electronegative atoms will be taken up by the electropositive atoms such that positive and negative ions are formed. Thus, $2N_2$ ions of opposite signs are obtained while the remainder electropositive levels N_1 - N_2 make the substance an *n*-type semi-conductor.

Q.7 a. Draw and explain the working of P-N Junction diode in forward & Reverse bias.

b.The resistance of the p & n layers of a silicon abrupt p-n junction are 10^{-2} & 10 Ohm respectively. The capacitance of the junction at zero applied bias voltage is 200 pF. If the thickness of the p & n layers are 1 mm. Each and the junction has a rectangular cross-section 1 mm².

(i) Determine concentration of impurity atoms on each side of the junction.

(ii) Width of depletion layer at zero applied voltage here μ_e = 1.45 $\times 10^3~cm^2/v\text{-sec}$ & μ_h = 0.5 \times 10 $^3~cm^2/v\text{-sec}$.

(iii) Find the contact potential.

(1) Contact potential

$$V_{D} = \frac{RA}{L} = \frac{15^{2} \times 0.001 \times 0.001}{0.001}$$

$$= 10^{-5}$$
for $n \text{ side} \quad f = 10^{-2}$
for $n \text{ solde} \quad \delta n = 10^{-5}$
for $n \text{ solde} \quad \delta n = 10^{-5}$

$$Bo \quad \delta n = Na \in Ve$$

$$Nd = \frac{\delta n}{e Ve} = \frac{10^{25}}{2.32} / m^{3}$$

$$4 \text{ Na} = \frac{\delta E}{e Vh} = \frac{10^{22}}{0.8} / m^{3}$$
(1) thick news of deputition larger
$$\chi = \frac{E_{0} E h}{C}$$
here Er is g.
(11) Contact potential

$$V_{0} = \frac{e}{2E_{0} E h} \left(\frac{Na Na}{Ha + Ma}\right)\chi^{2}$$

Q.8 Discuss working principal & applications of the following:) (i) Thermistors (ii) Electrolytic capacitors (iii) Cored coils (iv) Relay Ans(1) TBI/P.No. 266(ix) (2) TBI/P.No. 273(x)(3) TBI/P.No. 276(iii) (4) TBI/P.No. 276 section 12.2 first para Write short notes on the following: 0.9) (i) JFET (ii) Fabrication of transistors (i) 14.8. JFET JFET exists in several practically realizable geometries (Fig. 14.11) The cylindrical version is sometimes, used for discrete transistor manufacture. Planar form is most suitable for inclusion in I.Cs. Current i_d flows in the external circuit as shown in Fig. 14.11(d). Since the bulk of the material is n-type the current is transported in the semiconductor by majority electrons flowing from source to drain, the left hand contact is thus an electron source and the right-hand contact drains electrons out. Since the bar has an ohmic resistance, the flow of current in it produces an IR drop and the potential at any point in the bar increases from the source to the drain end, becoming more positive towards the drain. Therefore, since the gates have been shorted to the source, the pn junctions between the p-type gates and the n-type bar are reverse-biased, becoming progressively more so towards the drain end. Now, we know that the thickness of the depletion layer of a reverse biased pn junction varies approximately as the square root of the bias voltage. The layer QGI n-type OD Gz (a) Fig. 14.11(a). Cylindrical version of JFET







TEXTBOOK

I. Introduction to Electrical Engineering Materials by C.S. Indulkar and S. Thiruvengadam, 4th Edition, Reprint 2006 Edition, S. Chand and Company, New Delhi